

<b>Notice of References Cited</b>	Application/Control No. 10/084,432		Applicant(s)/Patent Under Reexamination DE LOYE ET AL.	
	Examiner Willie J. Daniel, Jr.		Art Unit 2617	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,116,682	10-2006	Waclawsky et al.	370/468
*	B	US-2002/0080744	06-2002	Ozluturk, Fatih M.	370/335
	C	US-			
	D	US-			
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	F	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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**NON-PATENT DOCUMENTS**

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